

10/581085  
AP3 Rec'd PCT/PTO 31 MAY 2006

PATENT

DK-US065116

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :  
Junko TAKAHASHI et al. :  
Serial No.: New – (National Phase of :  
PCT/JP2004/017779) :  
International filing date: November 30, 2004 :  
For: METHOD OF EXAMINING CHEMICAL :  
USING GENE-DISRUPTED STRAIN :

**INFORMATION DISCLOSURE STATEMENT**

Assistant Commissioner of Patents  
Washington, DC 20231

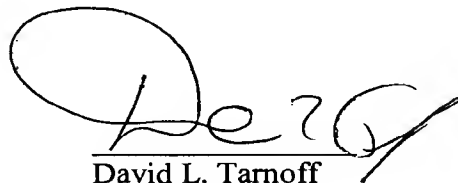
Sir:

In accordance with MPEP 609 and 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants bring the references listed on the attached PTO-1449-Form to the Examiner's attention and request that they be considered and made of record in this application. Copies of the non-U.S. patents are attached.

\* \* \*

Prompt examination on the merits is respectfully requested.

Respectfully submitted,

  
David L. Tarnoff  
Reg. No. 32,383

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Dated: 5-31-06

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /J.M./